Form PTO 1449 (Modified)		U.S. DEPARTMENT PATENT AND TRA	T OF COMMERCE ADEMARK OFFICE	ATTY DOCKET NO.		SERIAL NO.			
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	AO	JP 62-041223	02/23/1987	JAPAN (XP-002415423, English Abstra Thomson Scientific, Londong, GB only, previously submitted on August 26, 200	GB only, : 26, 2005)			×	
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